

Notice of References Cited

Application/Control No.

10/549,630

Applicant(s)/Patent Under
Reexamination
ITOH ET AL.

Examiner

Jennifer Y. Cho

Art Unit

1621

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0147136	10-2002	Von Wronski et al.	514/8
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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